TO TRADEMO Docket No. AMENDMENT TRANSMITTAL LETTER M4065.0159/P159-A Art Unit Application No. Filing Date Examiner 09/902,691 July 12, 2001 P. Brock 2815 Applicant(s): Li Li, et al Invention: METHOD OF CONTROLLING SRIATIONS AND CD LOSS IN CONTACT OXIDE ETCH TO THE COMMISSIONER FOR PATENTS Transmitted herewith is an amendment in the above-identified application. The fee has been calculated and is transmitted as shown below. **CLAIMS AS AMENDED** Highest Claims Number Remaining Number After Previously **Extra Claims** Amendment Paid Present Rate 0.00 **Total Claims** 27 28 Х Independent 2 3 0.00 х Claims Multiple Dependent Claims (check if applicable) Other fee (please specify): TOTAL ADDITIONAL FEE FOR THIS AMENDMENT: 0.00 Small Entity x Large Entity x No additional fee is required for this amendment. Please charge Deposit Account No. in the amount of \$ A duplicate copy of this sheet is enclosed. A check in the amount of \$ to cover the filing fee is enclosed. Payment by credit card. Form PTO-2038 is attached. × The Commissioner is hereby authorized to charge and credit Deposit Account No. as described below. A duplicate copy of this sheet is enclosed. x Credit any overpayment. Clarge any additional filing or application processing fees required under 37 CFR 1.16 and 1.17. Dated: January 15, 2003 Stephen A. Soffen Attorney Reg. No.: 31,063 DICKSTEIN SHAPIRO MORIN & OSHINSKY LLP 2101 L Street NW Washington, DC 20037-1526 (202) 828-2232

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Docket No.: M4065.0159

Group Art Unit: 2815

Examiner: P. Brock

(PATENT)

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Li Li, et al.

Application No.: 09/902,691

Filed: July 12, 2001

For: METHOD OF CONTROLLING

SRIATIONS AND CD LOSS IN CONTACT

OXIDE ETCH

## **AMENDMENT**

Box Non-Fee Amendment

\_Commissioner for Patents Washington, DC 20231

Dear Sir:

In response to the Office Action dated October 15, 2002 (Paper No. 6), please amend the above-identified U.S. patent application as follows:

## In the Claims

Please cancel claims 61, 63, and 65.

Please add new claims 94 and 95 as follows:

54. (New) The integrated circuit substrate of claim 59 wherein the critical dimension loss is reduced by about 400 angstroms.

95. (New) The integrated circuit substrate of claim 92 wherein the critical dimension loss is decreased by about 400 angstroms.

Please amend claims 59 and 92 as shown in the Replacement Claims:

1555846 v4; XCHY04!.DOC